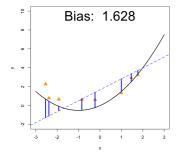
Introduction to Machine Learning

Advanced Risk Minimization Bias-Variance 1: Bias-Variance Decomposition



Learning goals

- Decompose GE of learner into
 - bias of learner
 - variance of learner
 - inherent noise of data
- Simulation study demo
- Capacity and overfitting



BIAS-VARIANCE DECOMPOSITION

• Generalization error of learner \mathcal{I} : Expected error of model $\mathcal{I}(\mathcal{D}_n) = \hat{f}_{\mathcal{D}_n}$, trained on set of size n, evaled on fresh test sample

$$GE_{n}(\mathcal{I}) = \mathbb{E}_{\mathcal{D}_{n} \sim \mathbb{P}_{xy}^{n}, (\mathbf{x}, y) \sim \mathbb{P}_{xy}} \left[L\left(y, \hat{f}_{\mathcal{D}_{n}}(\mathbf{x})\right) \right] = \mathbb{E}_{\mathcal{D}_{n}, xy} \left[L\left(y, \hat{f}_{\mathcal{D}_{n}}(\mathbf{x})\right) \right]$$

• \mathbb{E} taken over all train sets **and** independent test sample. Could also frame this as expected risk (expectation over \mathcal{D}_n)

$$\textit{GE}_{n}\left(\mathcal{I}\right) = \mathbb{E}_{\mathcal{D}_{n}}\left[\mathbb{E}_{\textit{xy}}\left[\textit{L}\left(\textit{y},\hat{\textit{f}}_{\mathcal{D}_{n}}(\textbf{x})\right)\right]\right] = \mathbb{E}_{\mathcal{D}_{n}}\left[\mathcal{R}(\hat{\textit{f}}_{\mathcal{D}_{n}})\right]$$

- For L2 loss, can additively decompose $GE_n(\mathcal{I})$ into 3 components
- Assume data is generated by

$$y = f_{\mathsf{true}}(\mathbf{x}) + \epsilon$$

with 0-mean homoskedastic error $\epsilon \sim (0, \sigma^2)$; independent of ${\bf x}$

 Similar decomps exist for other losses expressable as Bregman divergences (e.g. log-loss). One exception is 0/1



BIAS-VARIANCE DECOMPOSITION

$$\begin{aligned} \textit{GE}_n\left(\mathcal{I}\right) = \\ \underbrace{\sigma^2}_{\text{Var. of }\epsilon} + \mathbb{E}_{x} \underbrace{\left[\text{Var}_{\mathcal{D}_n}\left(\hat{\mathit{f}}_{\mathcal{D}_n}(\mathbf{x}) \mid \mathbf{x}\right) \right]}_{\text{Variance of learner at }\mathbf{x}} + \mathbb{E}_{x} \underbrace{\left[\left(\left(\mathit{f}_{\text{true}}(\mathbf{x}) - \mathbb{E}_{\mathcal{D}_n}\left(\hat{\mathit{f}}_{\mathcal{D}_n}(\mathbf{x})\right)\right)^2 \mid \mathbf{x}\right) \right]}_{\text{Squared bias of learner at }\mathbf{x}} \end{aligned}$$



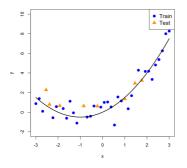
- First: variance of "pure" **noise** ϵ ; aka Bayes, intrinsic or irreducible error; whatever we we do, will never be better
- Second: how much $\hat{f}_{\mathcal{D}_n}(\mathbf{x})$ fluctuates at test \mathbf{x} if we vary training data, averaged over feature space; = learner's tendency to learn random things irrespective of real signal (overfitting)
- **3** Third: how "off" are we on average at test locations (underfitting); uses "average model integrated out over all \mathcal{D}_n "; models with high capacity have low **bias** and vice versa

SIMULATION EXAMPLE

• True model:

$$y = x + \frac{x^2}{2} + \epsilon$$
 $\epsilon \sim N(0,1)$

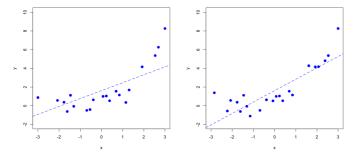
• Split in train and test sets





SIMULATION EXAMPLE

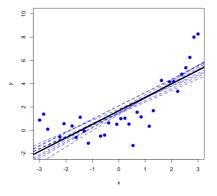
- Let's estimate bias and variance via bootstrapping
- (Could have also used Monte Carlo integration of the above quantities, BS slightly easier to visually explain)
- First, train several (low capacity) LMs
- These are the $\hat{t}_{\mathcal{D}_n}(\mathbf{x})$, seen as a RV, based on the random data \mathcal{D}_n





AVERAGE MODEL

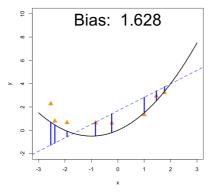
- Average model over different training datasets
- ullet This is $\mathbb{E}_{\mathcal{D}_n}[\hat{f}_{\mathcal{D}_n}(\mathbf{x})]$ in the decomp





SQUARED BIAS COMPUTATION / ESTIMATION

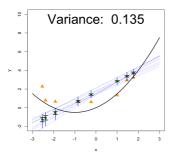
- Compute sq. diff. between avg. and true model at each test *x*
- Then average over all test points
- ullet This is $\mathbb{E}_{x}[(f_{\mathsf{true}}(\mathbf{x}) \mathbb{E}_{\mathcal{D}_{n}}(\hat{f}_{\mathcal{D}_{n}}(\mathbf{x})))^{2} \mid \mathbf{x})]$





VARIANCE COMPUTATION

- Compute variance of model predictions at each test x
- Then average over all test points
- This is $\mathbb{E}_{x}[\mathsf{Var}_{\mathcal{D}_{n}}(\hat{t}_{\mathcal{D}_{n}}(\mathbf{x}) \mid \mathbf{x})]$



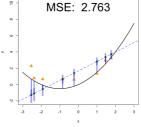
• Here, we know data variance $\sigma^2 = 1$; could also estimate it from residuals

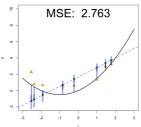


DECOMP RESULT AND COMPARISON WITH MSE

Decomp result; here bias is largest:

$$GE_n(\mathcal{I}) \approx 1 + 1.628 + 0.135 = 2.763$$

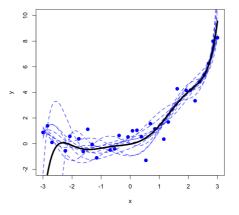




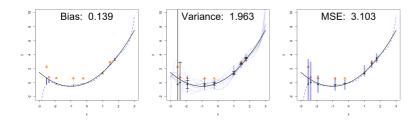
- Regular MSE: For each model, compute MSE on test set
- Then we average these MSEs over all models
- Result = 2.72; checks out; better if we avg. over more models and test points
- In general: Error quite high as we underfitted



• Same procedure, but using a high-degree polynomial (d = 7)







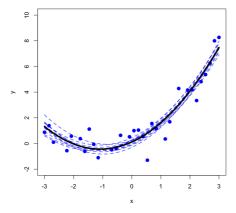


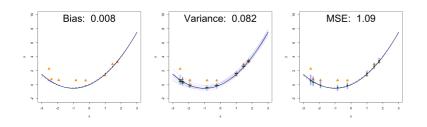
$$GE_n(\mathcal{I}) \approx 1 + 0.139 + 1.963 \approx 3.103$$

- GE higher than before, although hypo space now contains f_{true}
- Bias is lower, and variance higher
- Higher capacity learner overfits (here).
 We also do not regularize, that would be better
- NB: There is an "edge effect" on LHS, Runge effect, leads to higher bias as "artifact" here (ignore this)

 What happens if we use a model with the same complexity as the true model (quadratic polynomial)?





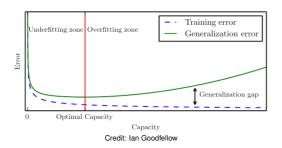




$$GE_n(\mathcal{I}) \approx 1 + 0.008 + 0.082 = 1.09$$

- Naturally: better result
- Low bias, low variance
- Bias should not be that much lower than high degree polynomial;
 but see comment there
- In any case, variance of the data is lower bound

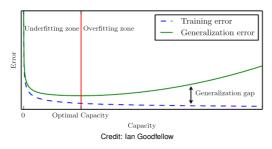
CAPACITY AND OVERFITTING





- Performance of a learner depends on its ability to
 - fit the training data well
 - generalize to new data
- Failure of the first point is called underfitting
- Failure of the second point is called overfitting

CAPACITY AND OVERFITTING





- The tendency of a learner to underfit/overfit is a function of its capacity, determined by the type of hypotheses it can learn
- ullet Usually: high capacity o low bias o better fit on train
- ullet But: high capacity o high variance o high chance of overfitting
- For such models, regularization (discussed later) is essential
- Even for correctly specified models, the generalization error is lower-bounded by the irreducible noise σ^2